

[IT-17. Atom probe and non-traditional microanalytical tasks](#)

10 September, 16:45 - 18:45 / 11 September, 16:30 - 18:30

IT-17-P-2954

Atom Probe Workbench for Materials Science & Engineering

Presenting author: **Ceguerra A. V.**

Authors: Ceguerra A. V., Stephenson L. T., Apperley M., Goscinski W. J., Ringer S. P.

IT-17-P-2966

Crystallographic calibration of Si-based atom probe reconstructions for enhanced short-range ordering information.

Presenting author: **Breen A. J.**

Authors: Breen A. J., Ceguerra A. V., Araullo-Peters V. J., Moody M. P., Ringer S. P.,

IT-17-P-3236

Improving Yield and Data Quality in Atom Probe Tomography

Presenting author: **Ulfig R. M.**

Authors: Larson D. J., Ulfig R. M., Prosa T. J., Lawrence D. F., Martin I. Y., Giddings A. D., Olson D. P., Kelly T. F.

IT-17-P-3469

The effects of laser wavelength and pulse energy on the measured oxide compositions by atom-probe tomography

Presenting author: **Kruska K.**

Authors: Kruska K., Lozano-Perez S., Schreiber D. K.

IT-17-P-5928

Quantitative evaluation of C, Mn and Si in martensite steels by atom probe tomography, electron microscopy and X-ray diffraction

Presenting author: **Kozuka M.**

Authors: Kozuka M., Otani S., Aruga Y.